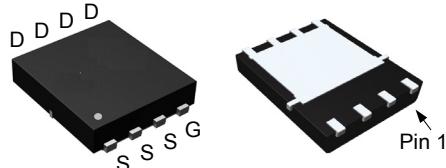


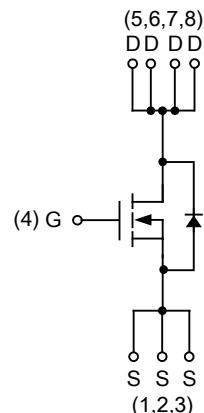
Features

- 40V/80A
 $R_{DS(ON)}=5\text{m}\Omega(\text{max.})@V_{GS}=10\text{V}$
 $R_{DS(ON)}=7.6\text{m}\Omega(\text{max.})@V_{GS}=4.5\text{V}$
- 100% UIS + R_g Tested
- Reliable and Rugged
- Lead Free and Green Devices Available
(RoHS Compliant)
- Moisture Sensitivity Level MSL1
(per JEDEC J-STD-020D)

Pin Description



DFN5x6-8_EP



N-Channel MOSFET

Applications

- Power Management in Desktop Computer or DC/DC Converters.

Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
XPX4080RD	XPX4080RD	DFN5X6-8L	-	-	-

Absolute Maximum Ratings ($T_A=25^\circ\text{C}$ Unless Otherwise Noted)

Symbol	Parameter	Rating	Unit
Common Ratings			
V_{DSS}	Drain-Source Voltage	40	V
V_{GSS}	Gate-Source Voltage	± 20	
T_J	Maximum Junction Temperature	175	$^\circ\text{C}$
T_{STG}	Storage Temperature Range	-55 to 175	$^\circ\text{C}$
I_S	Diode Continuous Forward Current	$T_C=25^\circ\text{C}$	40
I_D	Continuous Drain Current	$T_C=25^\circ\text{C}$	88
		$T_C=100^\circ\text{C}$	62
I_{DM}^a	Pulse Drain Current	$T_C=25^\circ\text{C}$	353
P_D	Maximum Power Dissipation	$T_C=25^\circ\text{C}$	68
		$T_C=100^\circ\text{C}$	34
$R_{\theta JC}$	Thermal Resistance-Junction to Case	Steady State	$^\circ\text{C}/\text{W}$
I_D	Continuous Drain Current	$T_A=25^\circ\text{C}$	16.4
		$T_A=70^\circ\text{C}$	13.7
I_{DM}^a	Pulse Drain Current	$T_A=25^\circ\text{C}$	65
P_D^b	Maximum Power Dissipation	$T_A=25^\circ\text{C}$	2.3
		$T_A=70^\circ\text{C}$	1.6
$R_{\theta JA}^b$	Thermal Resistance-Junction to Ambient	$t \leq 10\text{s}$	25
		Steady State	64
I_{AS}^c	Avalanche Current, Single pulse	$L=0.1\text{mH}$	27
E_{AS}^c	Avalanche Energy, Single pulse	$L=0.1\text{mH}$	36
			mJ

Note a : Pulse width is limited by max. junction temperature.

Note b : Surface mounted on 1in² pad area, steady state t = 999s.

Note c : UIS tested and pulse width limited by maximum junction temperature 175°C (initial temperature $T_j=25^\circ\text{C}$).

Electrical Characteristics ($T_A = 25^\circ\text{C}$ unless otherwise noted)

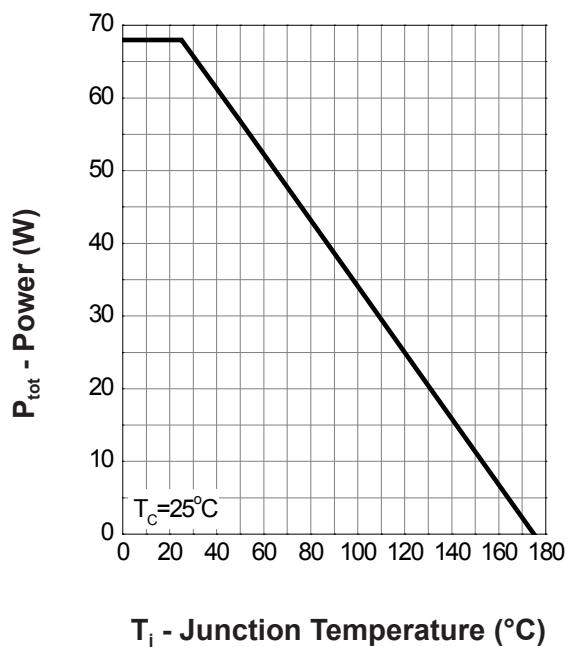
Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
Static Characteristics						
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}, I_{\text{DS}}=250\mu\text{A}$	40	-	-	V
I_{DSS}	Zero Gate Voltage Drain Current	$V_{\text{DS}}=32\text{V}, V_{\text{GS}}=0\text{V}$	-	-	1	μA
		$T_J=85^\circ\text{C}$	-	-	30	
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}, I_{\text{DS}}=250\mu\text{A}$	1.4	1.8	2.5	V
I_{GSS}	Gate Leakage Current	$V_{\text{GS}}=\pm 20\text{V}, V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
$R_{\text{DS(ON)}}^{\text{d}}$	Drain-Source On-state Resistance	$V_{\text{GS}}=10\text{V}, I_{\text{DS}}=20\text{A}$	-	4.2	5	$\text{m}\Omega$
		$T_J=125^\circ\text{C}$	-	6.3	-	
$V_{\text{GS}}=4.5\text{V}, I_{\text{DS}}=15\text{A}$		-	5.6	7.3		
G_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}, I_{\text{DS}}=15\text{A}$	-	25	-	S
Diode Characteristics						
V_{SD}^{d}	Diode Forward Voltage	$I_{\text{SD}}=20\text{A}, V_{\text{GS}}=0\text{V}$	-	0.85	1.1	V
t_r	Reverse Recovery Time	$I_{\text{DS}}=20\text{A}, dI_{\text{SD}}/dt=100\text{A}/\mu\text{s}$	-	23	-	ns
t_a	Charge Time		-	15	-	
t_b	Discharge Time		-	10	-	
Q_{rr}	Reverse Recovery Charge		-	15	-	
Dynamic Characteristics						
R_G	Gate Resistance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=0\text{V}, f=1\text{MHz}$	-	1	2	Ω
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}, V_{\text{DS}}=20\text{V}, \text{Frequency}=1.0\text{MHz}$	-	1370	1781	pF
C_{oss}	Output Capacitance		-	317	-	
C_{rss}	Reverse Transfer Capacitance		-	46	-	
$t_{\text{d(ON)}}$	Turn-on Delay Time	$V_{\text{DD}}=20\text{V}, R_L=20\Omega, I_{\text{DS}}=1\text{A}, V_{\text{GEN}}=10\text{V}, R_G=6\Omega$	-	13.3	24	ns
t_r	Turn-on Rise Time		-	7.9	15	
$t_{\text{d(OFF)}}$	Turn-off Delay Time		-	29.1	53	
t_f	Turn-off Fall Time		-	21	38	
Gate Charge Characteristics						
Q_g	Total Gate Charge	$V_{\text{DS}}=20\text{V}, V_{\text{GS}}=10\text{V}, I_{\text{DS}}=20\text{A}$	-	22	30.8	nC
Q_{gth}	Threshold Gate Charge		-	2.3	-	
Q_{gs}	Gate-Source Charge		-	4.2	-	
Q_{gd}	Gate-Drain Charge		-	3	-	

Note d : Pulse test ; pulse width $\leq 300\text{ms}$, duty cycle $\leq 2\%$.

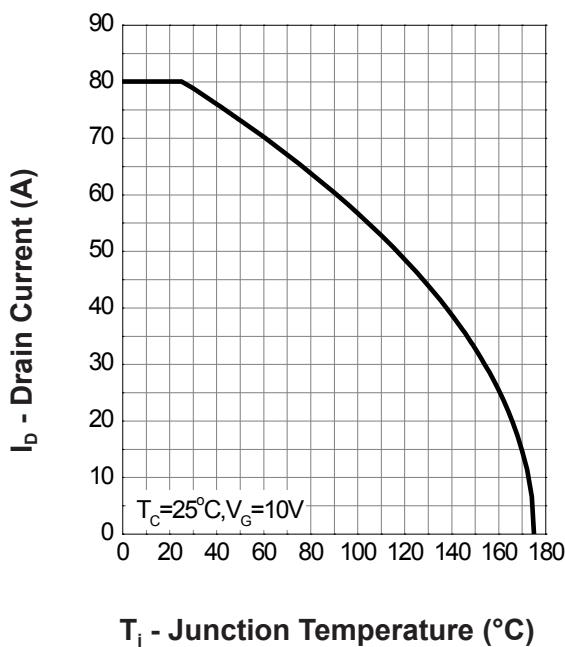
Note e : Guaranteed by design, not subject to production testing.

Typical Operating Characteristics

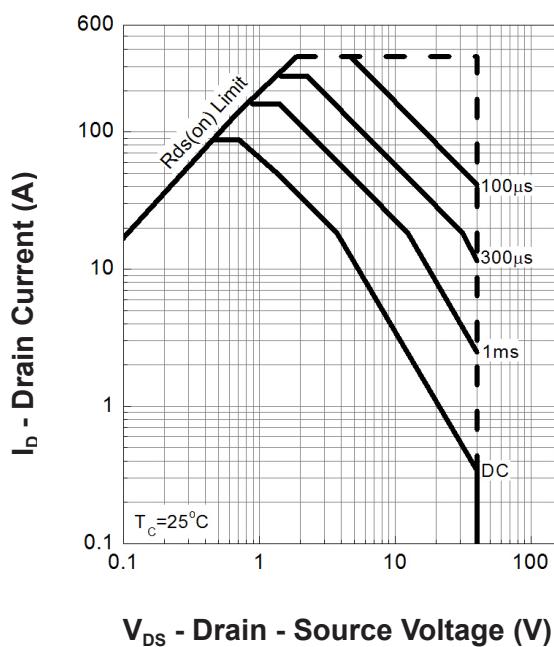
Power Dissipation



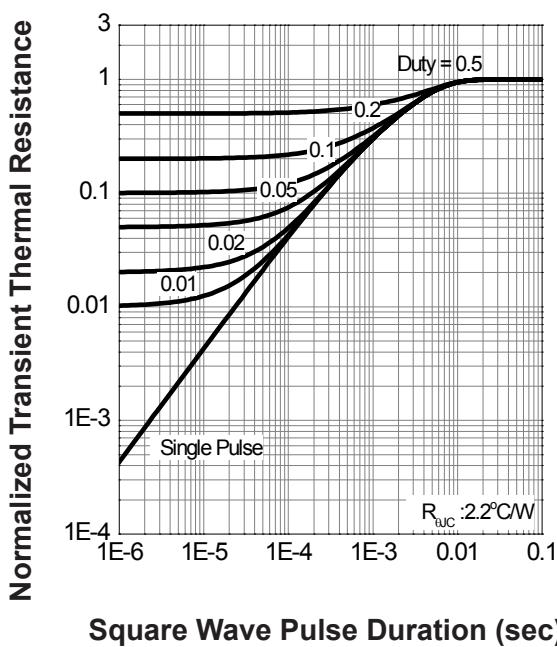
Drain Current



Safe Operation Area

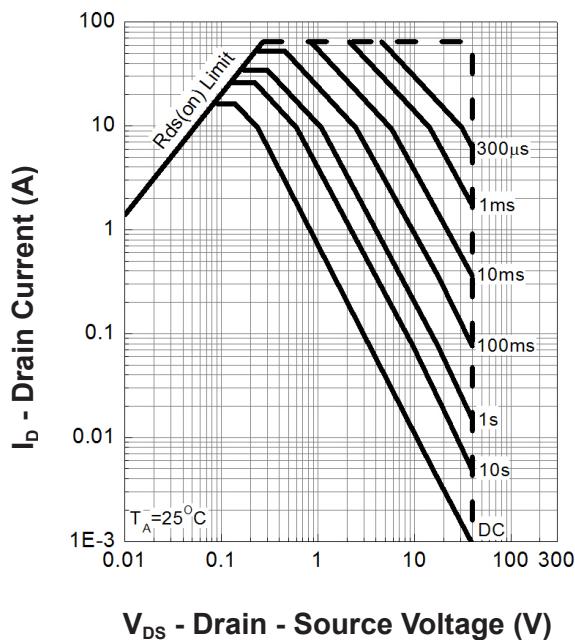


Thermal Transient Impedance

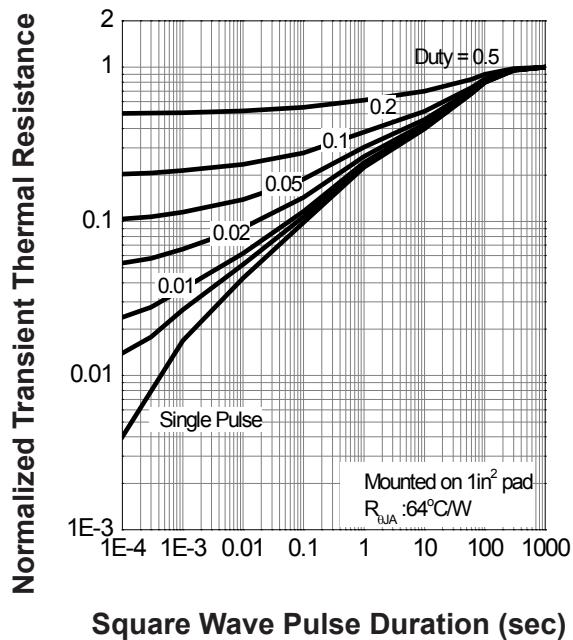


Typical Operating Characteristics(Cont.)

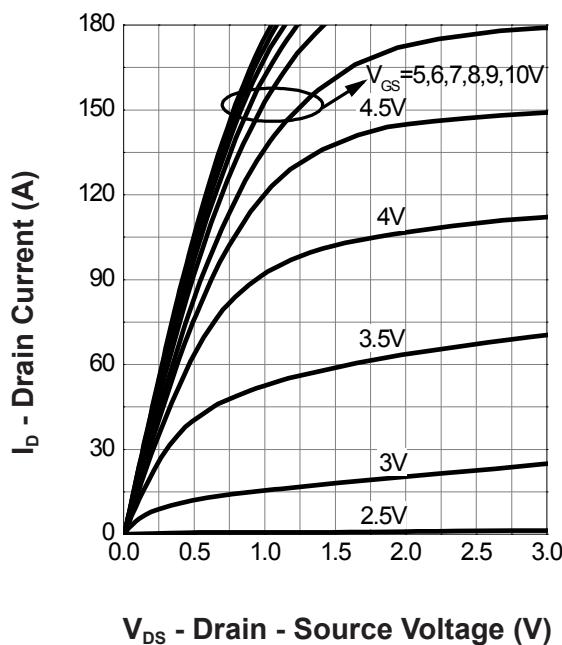
Safe Operation Area



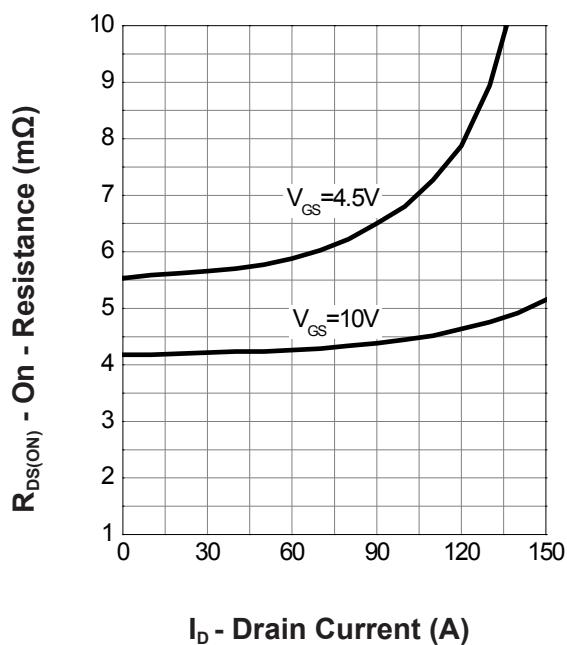
Thermal Transient Impedance



Output Characteristics

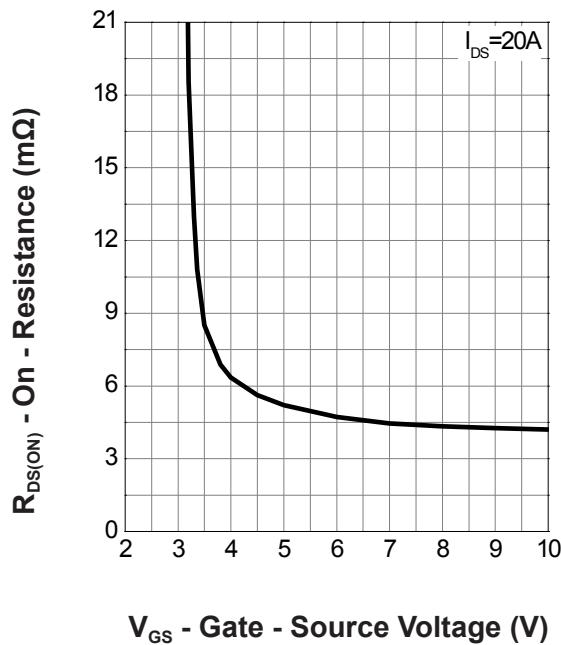


Drain-Source On Resistance

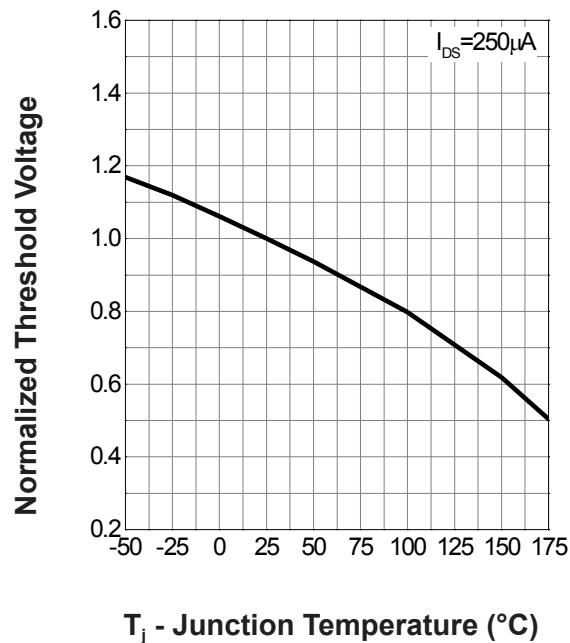


Typical Operating Characteristics(Cont.)

Gate-Source On Resistance



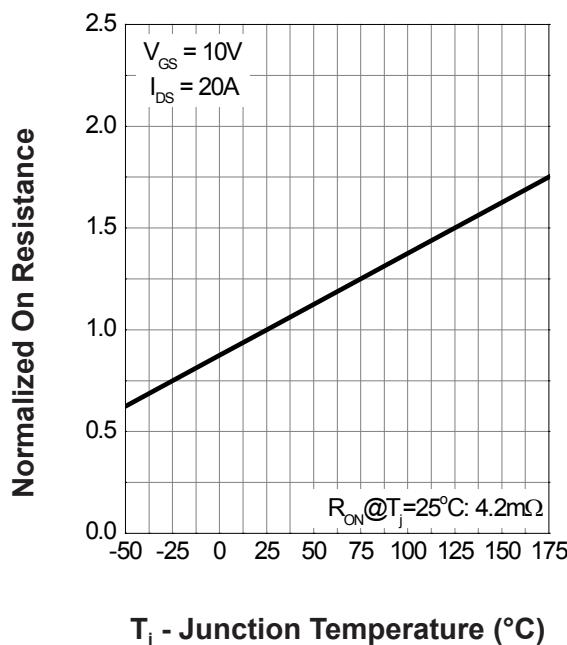
Gate Threshold Voltage



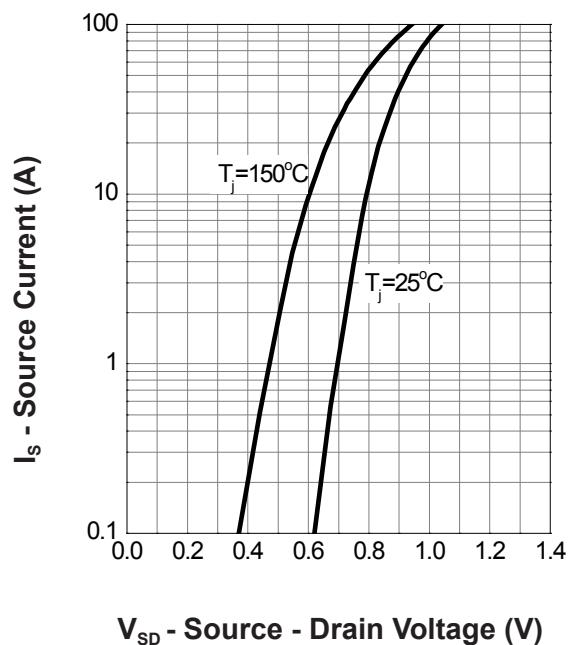
V_{GS} - Gate - Source Voltage (V)

T_j - Junction Temperature (°C)

Drain-Source On Resistance



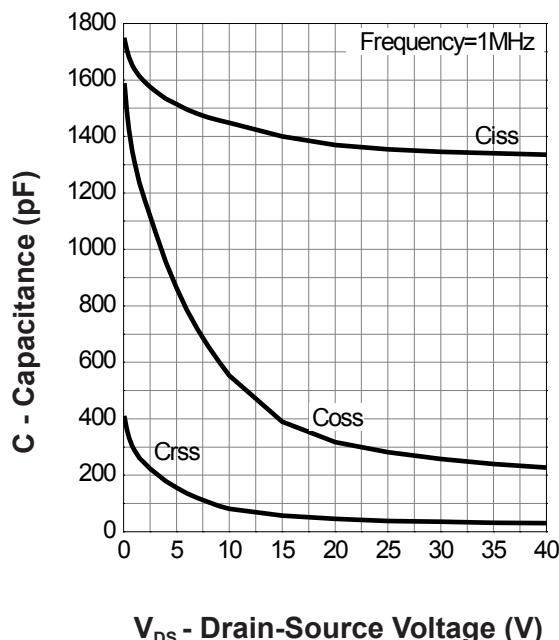
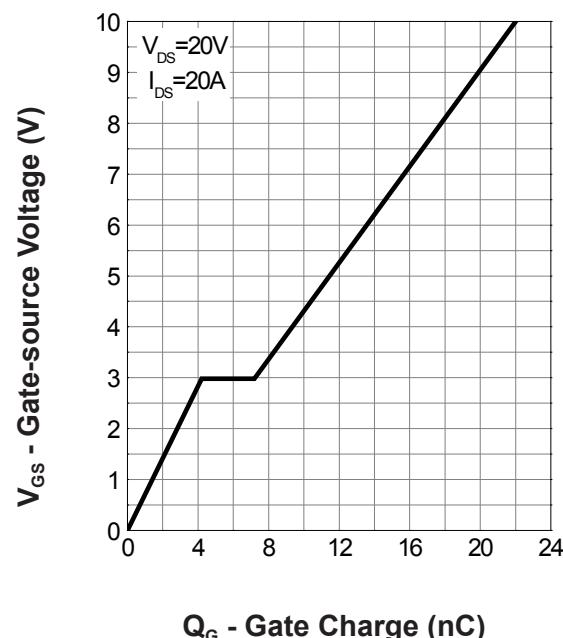
Source-Drain Diode Forward



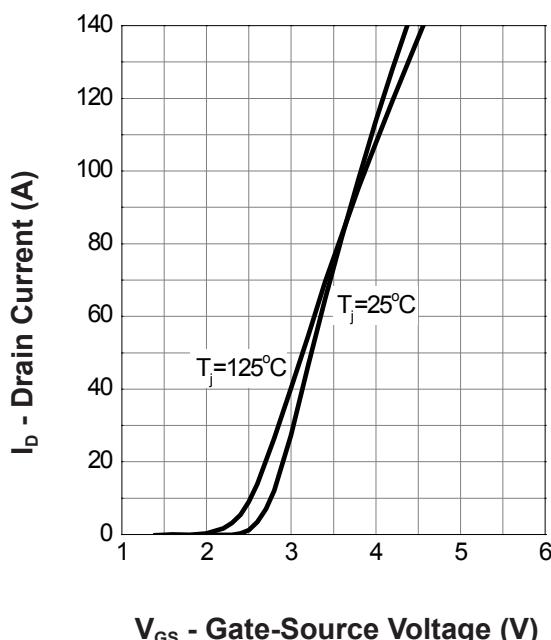
T_j - Junction Temperature (°C)

V_{SD} - Source - Drain Voltage (V)

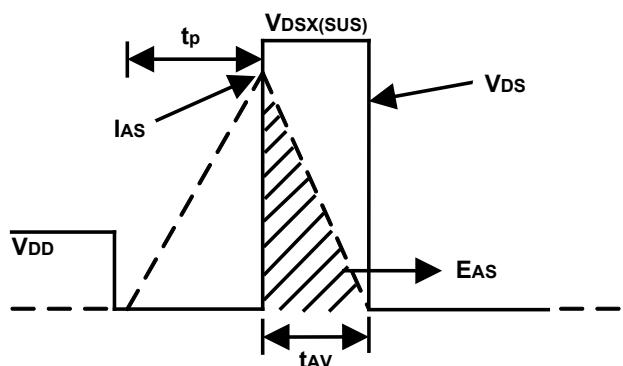
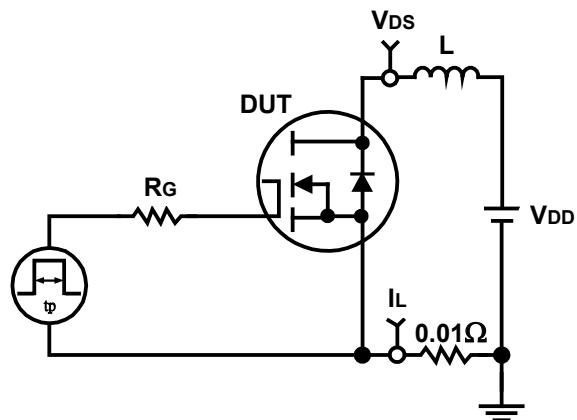
Typical Operating Characteristics(Cont.)

Capacitance

Gate Charge

 V_{DS} - Drain-Source Voltage (V)

 Q_G - Gate Charge (nC)

Transfer Characteristics

 V_{GS} - Gate-Source Voltage (V)

Avalanche Test Circuit and Waveforms



Switching Time Test Circuit and Waveforms

